TOSHIBA Insulated Gate Bipolar Transistor Silicon N Channel IGBT

GT40T302

Parallel Resonance Inverter Switching Applications

Unit: mm

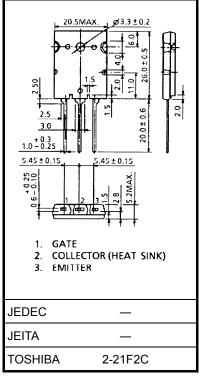
- FRD included between emitter and collector
- Enhancement mode
- High speed IGBT: $t_f = 0.23 \mu s$ (typ.) (I_C = 40 A)

FRD: $t_{rr} = 0.7 \mu s$ (typ.) (di/dt = $-20 \text{ A/}\mu s$)

• Low saturation voltage: $V_{CE (sat)} = 3.7 \text{ V (typ.)}$ (IC = 40 A)

Absolute Maximum Ratings (Ta = 25°C)

Characteristics		Symbol	Rating	Unit	
Collector-emitter voltage		V _{CES}	1500	V	
Gate-emitter voltage	V_{GES}	±25	V		
Collector current	DC	IC	40	А	
	1 ms	I _{CP}	80		
Diode forward current	DC	lF	30	А	
	1 ms	I _{FP}	80		
Collector power dissipation (Tc = 25°C)		P _C	200	W	
Junction temperature		Tj	150	°C	
Storage temperature range		T _{stg}	-55 to 150	°C	

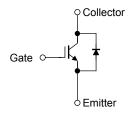


Weight: 9.75 g (typ.)

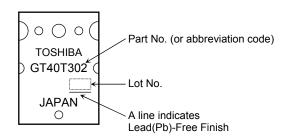
Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Equivalent Circuit



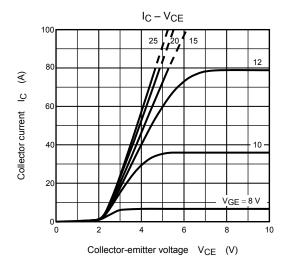
Marking

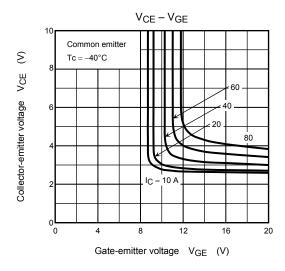


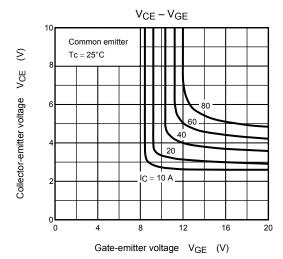
Electrical Characteristics (Ta = 25°C)

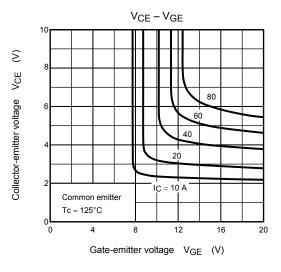
Characteristics		Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage current		I _{GES}	$V_{GE} = \pm 25 \text{ V}, V_{CE} = 0$	_	_	±500	nA
Collector cut-off current		I _{CES}	V _{CE} = 1500 V, V _{GE} = 0	_	_	1.0	mA
Gate-emitter cut-off voltage		V _{GE} (OFF)	I _C = 40 mA, V _{CE} = 5 V	4.0	_	7.0	V
Collector-emitter saturation voltage		V _{CE} (sat)	I _C = 40 A, V _{GE} = 15 V	_	3.7	5.0	V
Input capacitance		C _{ies}	$V_{CE} = 10 \text{ V}, V_{GE} = 0, f = 1 \text{ MHz}$	_	2900	_	pF
Switching time	Rise time	t _r	15 V 51 Ω CG	_	0.40	_	μs
	Turn-on time	t _{on}			0.45	_	
	Fall time	t _f		_	0.23	0.40	
	Turn-off time	t _{off}		_	0.6	_	
Diode forward voltage		V _F	I _F = 30 A, V _{GE} = 0	_	1.9	2.5	V
Reverse recovery time		t _{rr}	$I_F = 30 \text{ A}, V_{GE} = 0, \text{ di/dt} = -20 \text{ A/}\mu\text{s}$	_	0.7	3.0	μS
Thermal resistance		R _{th (j-c)}	IGBT	_	_	0.625	°CAM
			Diode	_	_	1.25	°C/W

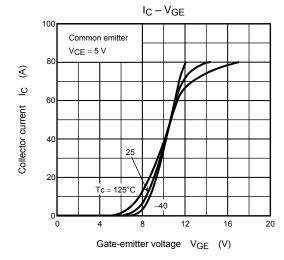
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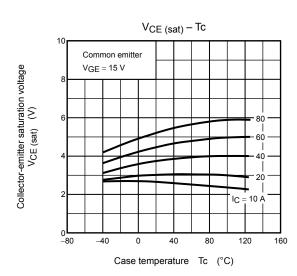




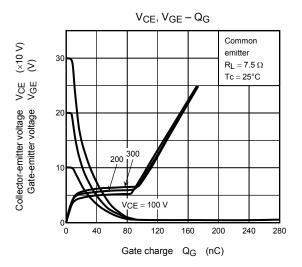


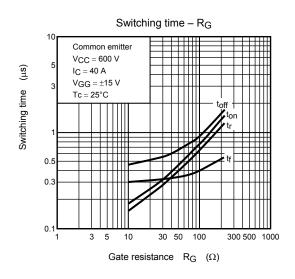


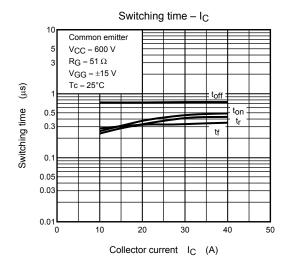


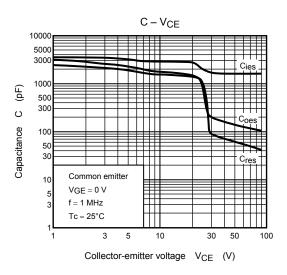


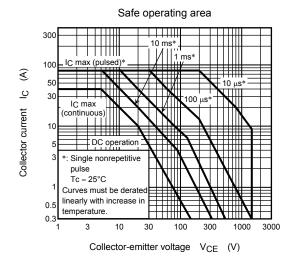
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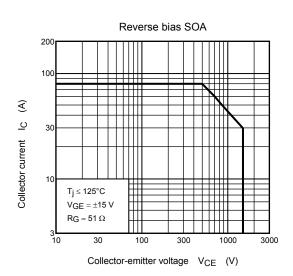


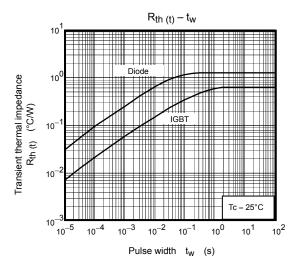


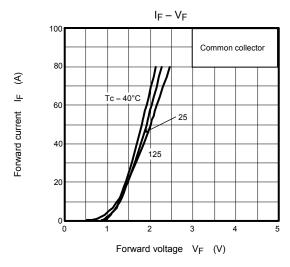


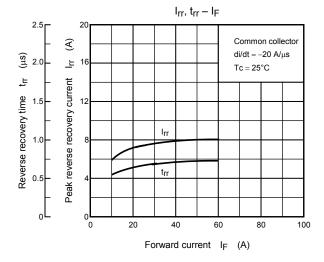


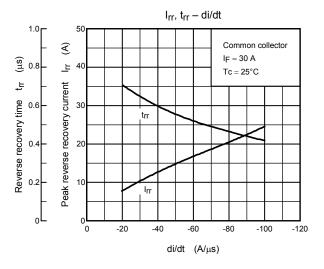












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